MSKSEMI















ESD

TVS

TSS

MOV

GDT

PLED

Broduct data speet





Features

- Ultra-Low capacitance:0.35pF(typ.)
- Reverse stand-off voltage:5V
- IEC 61000-4-2 (Air): ±15KV IEC 61000-4-2 (Contact): ±10KV

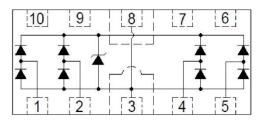
Pin Description



Applications

- USB 3.0, USB 2.0
- HDMI 1.3/1.4, Display Port 1.3, eSATA
- Unified Display Interface (UDI)
- Digital Visual Interface (DVI)
- High speed serial interfaces

Schematic Diagram



Top View

Limiting Values($T_A = 25$ °C, unless otherwise specified)

Symbol	Parameter	Conditions	Min	Max	Unit
V	Electrostatic Discharge Voltage	IEC 61000-4-2; Contact Discharge	-	±10	kV
V _{ESD}		IEC 61000-4-2; Air Discharge	-	±15	kV
I _{PPM}	Rated Peak Pulse Current	t _P = 8/20 μs	-	2.5	Α
T _A	Ambient Temperature Range	-	-55	125	$^{\circ}$
T _{stg}	Storage Temperature Range	-	-55	150	°C



Symbol	Parameter	Conditions	Min	Тур.	Max	Unit
V_{RWM}	Reverse Working Voltage	T _A = 25 °C	-	-	5	V
V _{BR}	Breakdown Voltage	I _R = 1 mA	6	7.2	9.5	V
I _R	Reverse Leakage Current	V _{RWM} = 5V	-	0.01	1	μΑ
Vc	Clamping Voltage	I _{PP} =2.5A, T _P =8/20µs	-	10	-	V
		V _{ESD} =+8kV	-	20	-	٧
V _T	Trigger Voltage	V _{ESD} =+8kV	-	135	-	V
Сл	Junction Capacitance	V _R = 0V, f = 1 MHz, I/O to I/O	-	0.15	-	pF
		V _R = 0V, f = 1 MHz, I/O to GND	-	0.35	-	pF

Typical Characteristics

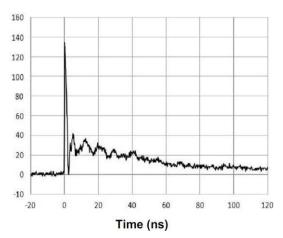


Fig.1 IEC61000-4-2 +8kV Contact ESD Clamping Waveform

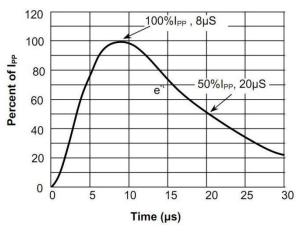


Fig.3 Pulse Waveform-8/20µs

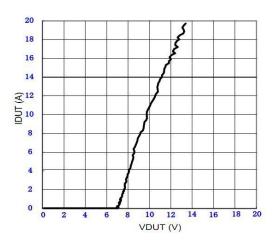


Fig.2 Transmission Line Pulse (t_P=100ns)

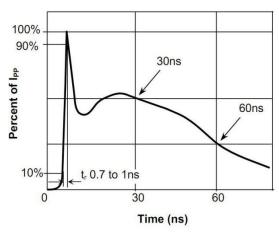


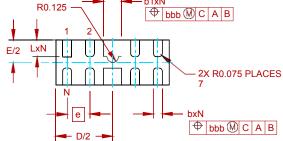
Fig.4 Pulse Waveform-ESD(IEC61000-4-2)



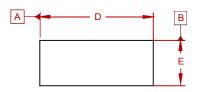


PACKAGE MECHANICAL DATA



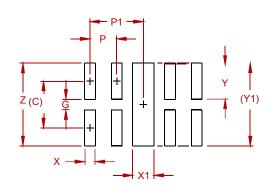


Dimensions in millimeters



DIMENSI ONS						
DIM	INCHES			MILLIMETERS		
J	MIN	NOM	MAX	MIN	NOM	MAX
Α	.020	.023	.026	0.50	0.58	0.65
A1	0.00	.001	.002	0.00	0.03	0.05
A2	(.005)		(0.13)			
b	.006	.008	.010	0.15	0.20	0.25
b1	.014	.016	.018	0.35	0.40	0.45
D	.094	.098	.102	2.40	2.50	2.60
E	.035	.039	.043	0.90	1.00	1.10
е	.020 BSC		0.50 BSC			
L	.012	.015	.017	0.30	0.38	0.425
N	8		8			
aaa	.003		0.08			
bbb	.004		0.10			

Suggested Pad Layout



DIMENSIONS				
DIM	INCHES	MILLIMETERS		
С	(.034)	(0.875)		
G	.008	0.20		
Р	.020	0.50		
P1	.039	1.00		
Х	.008	0.20		
X1	.016	0.40		
Υ	.027	0.675		
Y1	(.061)	(1.55)		
Z	.061	1.55		

NOTES:

CONTROLLING DIMENSIONS ARE IN MILLIMETERS (ANGLES IN DEGREES). THIS LAND PATTERN IS FOR REFERENCE PURPOSES ONLY. CONSULT YOUR MANUFACTURING GROUP TO ENSURE YOUR COMPANY'S MANUFACTURING GUIDELINES ARE MET.

REEL SPECIFICATION

P/N	PKG	QTY
MS1045-04F	DFN2510P10E	3000









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